# Control of $0.2 \mathrm{CaTiO}_{3}-\mathbf{0 . 8 L i}_{0.5} \mathbf{N d}_{0.5} \mathrm{TiO}_{3}$ microwave dielectric ceramics by additions of $\mathrm{Bi}_{2} \mathbf{T i}_{2} \mathbf{O}_{7}$ 

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#### Abstract

Ceramics of $0.2 \mathrm{CaTiO}_{3}-0.8 \mathrm{Li}_{0.5} \mathrm{Nd}_{0.5} \mathrm{TiO}_{3}$ ) have been prepared by the mixed oxide route using additions of $\mathrm{Bi}_{2} \mathrm{O}_{3}-2 \mathrm{TiO}_{2}$ (up to $15 \mathrm{wt} \%$ ). Powders were calcined $1100^{\circ} \mathrm{C}$; cylindrical specimens were fired at temperatures in the range $1250-1325^{\circ} \mathrm{C}$. Sintered products were typically $95 \%$ dense. The microstructures were dominated by angular grains $1-2 \mu \mathrm{~m}$ in size. With increasing levels of $\mathrm{Bi}_{2} \mathrm{O}_{3}-2 \mathrm{TiO}_{2}$ additions, needle and lath shaped second phases developed. For $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions up to $5 \mathrm{wt} \%$, the relative permittivity increased from 95 to 131 , the product of dielectric $Q$ value and measurement frequency increased from 2150 to 2450 GHz and the temperature coefficient of resonant frequency $\left(\tau_{f}\right)$ increased from $-28 \mathrm{pp} /{ }^{\circ} \mathrm{C}$ to $+22 \mathrm{pp} /{ }^{\circ} \mathrm{C}$. A product with temperature stable $\tau_{f}$ could be obtained at $\sim 2 \mathrm{wt} \%$ $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions. For high levels of additives, there is minimal change in relative permittivity, the Qxf values degrade and $\tau_{f}$ becomes increasingly negative.


Keywords Perovskite - $\mathrm{CaTiO}_{3}$ - Microwave dielectric Electron BackScatter Diffraction (EBSD)

## Introduction

The demand by the telecommunications industry for the miniaturization of microwave components [1] can be achieved by increasing the relative permittivity $\left(\varepsilon_{r}\right)$ since the size of microwave components is inversely proportional to the square root of the relative permittivity. Additional requirements are that the microwave losses should be minimized (or the $Q$ value maximized) and the dielectric properties

[^0]be temperature stable such that the temperature coefficient of resonant frequency ( $\tau_{f}$ ) is close to zero ( $\pm 5 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$ ). A number of materials that have similar crystal structures but opposite $\tau_{f}$ can be combined to produce a ceramic with microwave properties that can be tailored to specific applications. One such combination of ceramics is the system $\mathrm{CaTiO}_{3}-\mathrm{Li}_{x} \mathrm{Ln}_{1-x} \mathrm{TiO}_{3}(\mathrm{Ln}=\mathrm{Sm}, \mathrm{Nd})$ that has attracted interest [2-6] because of its high $\varepsilon_{r}$. Both end members in the system are distorted perovskites with high, but opposite, nonzero $\tau_{f}$ values. The $\mathrm{CaTiO}_{3}-\mathrm{Li}_{x} \mathrm{Ln}_{1-x} \mathrm{TiO}_{3}(\mathrm{Ln}=\mathrm{Sm}, \mathrm{Nd})$ system has been shown to exhibit good dielectric properties for compositions having $x$ in the range $2-3[2,6]$, although the Nd analogue exhibits higher relative permittivity $[6,7]$. The use of $\mathrm{Bi}_{2} \mathrm{O}_{3}$ additions has been shown to be beneficial to both $\mathrm{BaO}-\mathrm{Nd}_{2} \mathrm{O}_{3}-\mathrm{TiO}_{2}[8-10]$ and $0.4 \mathrm{CaTiO}_{3}-0.6 \mathrm{Li}_{0.5} \mathrm{Nd}_{0.5} \mathrm{TiO}_{3}$ [6] based ceramics. In this study the effect of $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ addition to $0.2 \mathrm{CaTiO}_{3}-0.8 \mathrm{Li}_{0.5} \mathrm{Nd}_{0.5} \mathrm{TiO}_{3}(0.2 \mathrm{CT}-0.8 \mathrm{LNT})$ has been investigated, with a view to producing a temperature stable dielectric material and determining the important structural changes that result from the presence of bismuth.

## Experimental

Ceramics of the $0.2 \mathrm{CT}-0.8 \mathrm{LNT}$ were prepared by the mixed oxide route using $\mathrm{CaTiO}_{3}\left(99 \%\right.$-ALFA AESAR), $\mathrm{Li}_{2} \mathrm{CO}_{3}$ ( $99 \%$-Fluka), $\mathrm{Nd}_{2} \mathrm{O}_{3}$ ( $99 \%$-Honeywell Electronic Materials) and $\mathrm{TiO}_{2}$ ( $98.5 \%$-Tioxide UK Ltd). After mixing, the powders were wet milled in Propan-2-ol for 16 hours, and calcined at $1100^{\circ} \mathrm{C}$ for four hours. $\mathrm{Bi}_{2} \mathrm{O}_{3}-2 \mathrm{TiO}_{2}(\mathrm{BT})$ was added and the mixture ball milled for a further 16 h . Cylindrical samples were pressed 60 MPa . For firing they were placed on an alumina support covered in the starting material; the pellets were embedded in starting material and covered by an alumina housing to minimize Li loss. Sintering was performed in
a horizontal tube furnace at temperatures in the range $1250^{\circ}$ to $1325^{\circ} \mathrm{C}$ for three hours. Product densities were determined by weight and dimension measurements.

X-ray diffraction was undertaken using a Philips X'PERT system ( $P W$ 3710) over the $2 \theta$ range $10^{\circ}$ to $100^{\circ}$ with a step size of $0.04^{\circ}$. Lattice parameters were determined using CELLREF software. For microstructural analysis all specimens were ground on 1200 grade SiC and then successively polished on $6 \mu \mathrm{~m}, 1 \mu \mathrm{~m}$ and $0.25 \mu \mathrm{~m}$ diamond paste followed by OPS (colloidal Silica suspension) for five hours. The samples were investigated in detail by scanning electron microscopy (Philips SEM525 equipped with an EDAX DX4 system). Additional studies were carried out under electron backscatter diffraction (EBSD) conditions using a Philips XL30 FEG SEM. Charging of the sample surface during EBSD was prevented by applying a thin carbon layer that was overlain by a mesh network of metallic silver. The relative permittivity was measured by the Hakki and Coleman parallel plate [11] method whilst the dielectric $Q$ value (reported as product of Qxf , where $f$ is the measurement frequency) by the cavity method; $\tau_{f}$ was determined between $-20^{\circ}$ and $+60^{\circ} \mathrm{C}$.

## Results and discussion

Undoped ceramics of 0.2CT-0.8LNT achieved 95\% theoretical density after firing at the optimum temperature of $1325^{\circ} \mathrm{C}$. The addition of bismuth titanate to 0.2CT-0.8LNT reduced the optimum sintering temperature of the solid solution, by up to $75^{\circ} \mathrm{C}$ in the case of $15 \mathrm{wt} \%$ additions (Fig. 1). X-ray diffraction analysis confirmed that products exhibited an orthorhombic perovskite structure. All the spectra were very similar to that for $\mathrm{CaTiO}_{3}$ [6] and could be indexed on the basis of Pbnm (No. 62), indicating in-phase and anti-phase tilting $\left(a^{+} b^{-} b^{-}\right)$with A-site cation ion displacement, according to Glazers classification [12]. The


Fig. 1 Sintered density and optimum sintering temperature ( ${ }^{\circ} \mathrm{C}$ ) for $0.2 \mathrm{CT}-0.8 \mathrm{LNT}$ as a function of bismuth titanate additions: Density ( $\mathbf{\Delta}$ ) and sintering temperature


Fig. 2 Lattice parameters for 0.2CT-0.8LNT ceramics as a function of bismuth titanate additions: $a$-axis $(\cdot \bullet), b$-axis ( $\mathbf{\square})$ and $c$-axis ( $\mathbf{\Delta}$ )
tilting mechanisms of 0.2CT-0.8LNT do not appear to be affected by the addition of bismuth titanate. This is similar to the findings of Lowe et al [6] for the behaviour of 0.4CT0.6 LNT ceramics. Figure 2 shows the lattice parameters for $0.2 \mathrm{CT}-0.8 \mathrm{LNT}$ as a function of bismuth titanate additions. With the addition of $5 \mathrm{wt} \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ to 0.2CT-0.8LNT, the a and b axes increase from $5.390 \AA$ and $5.436 \AA$ to 5.394 $\AA$ and $5.443 \AA$ respectively. Further additions of bismuth titanate to 0.2CT-0.8LNT do not have a significant effect on the lengths of the $a$ and $b$ axes. In contrast the length of the $c$ axis exhibited minimal variation with composition, although there is a suggestion of a sight reduction with increasing $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions. On the basis of ionic radii, it is anticipated that Bi (coordination 6, ionic radius $1.17 \AA$ [13]) is incorporated into the perovskite structure on the A site. The fact that the cell parameters increase only for samples prepared with up to $5 \mathrm{wt} \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions suggests that the solubility limit for Bi is reached between 5 and $10 \%$.

Typical microstructures for 0.2CT-0.8LNT ceramics are shown in Fig. 3. The grains are angular in shape and tend to decrease in size as the amount of $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ in the starting formulation increases. In undoped 0.2CT-0.8LNT there is obvious variability in the grain size (Fig. 3(a)), with grains between $1 \mu \mathrm{~m}$ and $5 \mu \mathrm{~m}$ (average $2.6 \mu \mathrm{~m}$ ). For $10 \mathrm{wt} \%$ $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions the grain size reduced to $1.4 \mu \mathrm{~m}$ although there is still extensive twinning, reflecting the effect of the $\mathrm{CaTiO}_{3}$ component (Fig. 3(b)). At $15 \mathrm{wt} \%$ additions there is clear evidence of small lath shaped grains as well as the twinned primary grains (Fig. 3(c)). Energy dispersive spectroscopy (EDS) indicated that the bismuth-rich second phase is $\mathrm{Bi}_{4} \mathrm{Ti}_{3} \mathrm{O}_{12}$. The brighter rims to the grain boundaries indicates the possibility of segregation of atoms of higher atomic number.

Figure 4 shows the variation in relative permittivity and Qxf value as a function of bismuth titanate additions. Modest additions of $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ (up to $5 \mathrm{wt} \%$ ) result in a rapid increase in the relative permittivity from 95 to 131, but there


Fig. 3 Electron back scattered images of 0.2CT-0.8LNT ceramics prepared with different amounts of $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions: (a) $0 \mathrm{wt} \%$; (b) $10 \mathrm{wt} \%$, (c) $15 \mathrm{wt} \%$; A represents calcium rich regions, $\mathbf{B}$ indicates the


Fig. 4 Relative permittivity ( $\mathbf{\Delta}$ ) and $\operatorname{Qxf}(\bullet)$ for 0.2CT-0.8LNT as a function of bismuth titanate additions
is minimal change thereafter. The dielectric Qxf value shows a similar increase for low levels of additions (from 2150 to 2450 GHz ) but beyond the peak at $5 \mathrm{wt} \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ the Qxf value decreases, returning to 2150 GHz at $15 \mathrm{wt} \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$.

The initial increase in relative permittivity can be attributed in part to the incorporation of Bi into the perovskite
presence of twinning, $\mathbf{C}$ indicates bismuth rich laths and $\mathbf{D}$ indicates bismuth rich second phase
structure; the stabilisation in $\varepsilon_{r}$ at $5-10 \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ reflects the fact that the solubility limit is reached, with clear evidence of a Bi-rich second phase for samples prepared with $15 \mathrm{wt} \%$ $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ (Fig. 3(c)). Whilst polarisability changes resulting from ionic substitutions have a significant impact on relative permittivity, further insight into dielectric behaviour can be gained from consideration of bond valence or bond strength concepts [14]. The bond valences for the A-site and B-site in 0.2CT-0.8LNT have been calculated $[14,15]$ as a function of $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions (Fig. 5). The addition of bismuth titanate to $0.2 \mathrm{CT}-0.8 \mathrm{LNT}$ results in a linear increase of the A site bond valence while the B site bond valence decreases linearly up to $5 \mathrm{wt} \%$. This suggests that Bi additions cause the A-site to become more constrained, although, according to Park et al. [14] the A site bond valence has little effect upon the relative permittivity. In contrast, the reduction in the B -site bond valence (up to $5 \mathrm{wt} \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ ) means the highly polarisable Ti ions can be readily be displaced within the structure, leading to enhanced relative permittivity.

It was noted above that the Qxf values initially increase (along with $\varepsilon_{r}$ ) but subsequently decrease (Fig. 4). The


Fig. 5 The A site bond valence ( $\mathbf{\Delta}$ ) and B site bond valence ( $\bullet$ ) for $0.2 \mathrm{CT}-0.8 \mathrm{LNT}$ as a function of bismuth titanate additions
decrease in Qxf at higher levels of $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions can be attributed to the appearance of the second phase. Some understanding of the reason for the increase in Qxf for bismuth titanate additions below $5 \mathrm{wt} \%$ may be gained by considering the anharmonicity of the system. A crude measure of the change in lattice anharmonicity $(\mu)$ with bismuth titanate addition can be achieved through Eq. (1) [16], where $k_{b}$ is Boltzmanns constant, $T$ is temperature, $M$ is the atomic mass of the unit cell and $v$ is the mean velocity of sound. As no published value for $\mathrm{CaTiO}_{3}$ could be found, the value for the related material $\mathrm{LaAlO}_{3}$ (an orthorhombic perovskite), was adopted.
$\mu=\frac{k_{b} T}{M v^{2}}$
Equation (1) essentially predicts that anharmonicity and Qxf values for 0.2CT-0.8LNT will increase upon addition of bismuth titanate. Clearly the simple relationship fails at high levels of $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions when second phases form and the Qxf values reduce.

The final dielectric parameter for 0.2CT-0.8LNT is the temperature coefficient of resonant frequency $\left(\tau_{f}\right)$. As bis-


Fig. $6 t_{f}(\mathbf{\Delta})$ and tolerance factor $(\bullet)$ for 0.2CT-0.8LNT as a function of bismuth titanate additions
muth titanate content increases (Fig. 6), the $\tau_{f}$ value increases from $-28 \mathrm{pp} /{ }^{\circ} \mathrm{C}$ (zero additions) to $4 \mathrm{ppm} /{ }^{\circ} \mathrm{C}(2.5 \mathrm{wt} \%$ $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ ) to $+22 \mathrm{pp} /{ }^{\circ} \mathrm{C}\left(5 \mathrm{wt} \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}\right)$. For higher levels of bismuth titanate additions, the $\tau_{f}$ value decreases steadily to $-40 \mathrm{pp} /{ }^{\circ} \mathrm{C}\left(15 \mathrm{wt} \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}\right)$. The polarity changes in the $\tau_{f}$ value mirror changes in the Qxf values (Fig. 4).

Reaney et al. [17] identified an empirical relationship between the tolerance factor $\left(t_{o}\right)$ and $\tau_{f}$, for number of different compositions. They showed that for dielectric materials exhibiting in-phase and anti-phase tilting ( $t_{o}<0.964$ ), the $\tau_{f}$ would decrease towards zero as the tolerance factor increased. For the present $0.2 \mathrm{CT}-0.8 \mathrm{LNT}$ ceramic system, it is noted (Fig. 6) that both $t_{o}$ and $\tau_{f}$ increase for $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions up to $5 \mathrm{wt} \%$, but at higher levels $\tau_{f}$ decreases whilst the tolerance factor continues to increase. Thus the simple relationship between $t_{o}$ and $\tau_{f}$ does not hold for 0.2CT-0.8LNT prepared with $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ additions. An alternative way of exploring changes in $\tau_{f}$, is the bond valence approach.

As bismuth titanate is added to $0.2 \mathrm{CT}-0.8 \mathrm{LNT}$, the substitution of $\mathrm{Ca}^{2+}$ by $\mathrm{Bi}^{3+}$ on the A -site results in an increase in the A -site bond valence while the B -site bond valence decreases (Fig. 5). As $\tau_{f}$ increases from $-28 \mathrm{pp} /{ }^{\circ} \mathrm{C}$ (zero additions) towards $\sim 0 \mathrm{pp} /{ }^{\circ} \mathrm{C}$ at $\sim 2.0 \mathrm{wt} \% \mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$, the $\mathrm{A}-$ site bond valence increases. There is as yet no obvious link for a trend between $\tau_{f}$ and the A site bond valence. However, the B -site bond valence decreases with increasing bismuth titanate content and it has been reported [18] that as B-site bond valence decreases the $\tau_{f}$ approaches zero. As the B-site ions are related directly to the degree of tilting in the structure, then as the B site bond valence decreases (for tilted structures), there is a reduction in the restoring force (term A in the differentiated Claussius Mosotti equation [19]) and this leads to a reduction in $\tau_{f}$. This implies that the restoring force is reduced to an optimum value, resulting in a temperature stable material when $2.5 \mathrm{wt} \%$ bismuth titanate is added to $0.2 \mathrm{CT}-0.8 \mathrm{LNT}$. However, higher additions cause $\tau_{f}$ to become first positive and then negative once more. Above $5 \mathrm{wt} \%$ bismuth titanate the B site bond valence remains constant, indicating that the bismuth titanate does not have any significant effect and other extrinsic factors, including the presence of second phases, become more important.

## Conclusions

Good quality ceramics of $0.2 \mathrm{CaTiO}_{3}-0.8 \mathrm{Li} 0.5 \mathrm{Nd} 0.5 \mathrm{TiO}_{3}$ were prepared by the mixed oxide route. Small additions of $\mathrm{Bi}_{2} \mathrm{Ti}_{2} \mathrm{O}_{7}$ ) resulted in a significant increase in the relative permittivity, a small increase in the Q.f. value and reduction in $\tau_{f}$ towards zero. At higher levels of additions, second phases, rich in bismuth develop as laths with the primary grains. This is accompanied by a small reduction in $\varepsilon_{r}$, a significant reduction in Qxf and $\tau_{f}$ becomes increasingly
negative. Small additions of Bismuth Titanate may be used to tune the microwave properties of 0.2CT-0.9LNT, to yield ceramics with optimum microwave properties.

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